


<b><i>Search Notes</i></b>  	<b>Application/Control No.</b>  10576850	<b>Applicant(s)/Patent Under Reexamination</b>  PARK ET AL.
	<b>Examiner</b>  John P Sheehan	<b>Art Unit</b>  1793

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search	12/18/2009	JPS
EAST Search Update	7/13/2010	/JPS/
EAST Update See Search History Printout	3/14/2011	/JPS/

INTERFERENCE SEARCH			
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